Supporting Information

Synthesis and Structural Analysis of Dimethylaminophenyl-End-

Capped Diketopyrrolopyrrole for Highly Stable Electronic

Devices with Polymeric Gate Dielectric

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Figure S3. AFM height image (5 μ m x 5 μ m) of DPP(PhNMe₂)₂ thin-film prepared on a OTS treated Si/SiO₂ substrate.



Figure S4. Typical (a) output and (b) transfer characteristic curves of bottom-gate top-contact OFETs comprising a DPP(PhNMe₂)₂ film on a OTS treated SiO₂ gate dielectric.



Figure S5. Operational stability of OTFT device based on OTS-SiO₂ gate dielectric evaluated by repeated (100 times) recording of (a) the drain current as a function of drain voltage at gate voltage of -40 V, (b) the drain current as a function of gate voltage at a drain voltage of -40 V, (c) Device operational stability tested by applying a square wave (amplitude 0 to -40 V) to the gate and a constant drain voltage of -40 V to the drain.



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